



SCALABLE QUANTUM BIT CONTROL (SQUBIC1)

Cryogenic CMOS IC for Spin Qubit Control

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FORSCHUNGSZENTRUM JÜLICH - ELECTRONIC SYSTEMS (ZEA-2)

QUANTUM COMPUTERS

General Introduction

- Possible **exponential speed up** for certain tasks:
 - Shor's algorithm for **factoring integers**
 - Grover's algorithm for **search in unordered databases**
 - **Quantum chemistry**: Simulate new molecules and catalysts
 - Quantum(-enhanced) machine learning
- Requirements for a universal quantum computer:
 - **Large number (10^6 - 10^8) of physical qubits^[1]** (operated at $T \lesssim 1\text{K}$)
 - Room temperature electronics to communicate with the qubits
 - **Scalable control and read-out electronics**

[1] Vandersypen, L.M.K., Bluhm, H., Clarke, J.S. *et al.* Interfacing spin qubits in quantum dots and donors—hot, dense, and coherent. *npj Quantum Inf* **3**, 34 (2017). <https://doi.org/10.1038/s41534-017-0038-y>



QUANTUM COMPUTERS

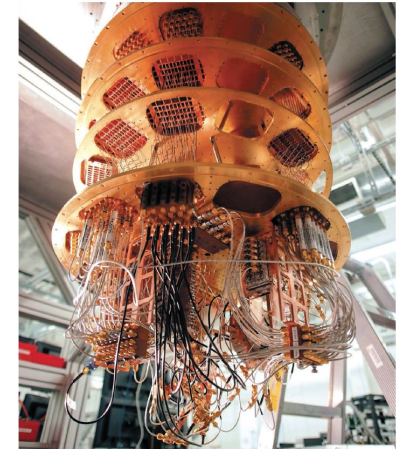
Current Approaches

- 'Brute force' scaling to operate up to 50-100 qubits
- Further scaling very difficult
- The 'Tyranny of numbers' (Jack Morton, Bell Labs, 1958) is back
- **Let's solve it (again) with integrated circuits**

Today

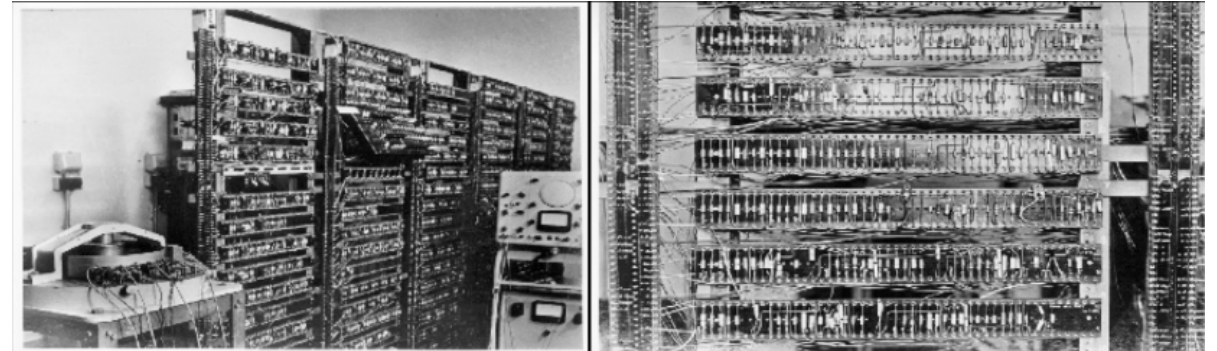


Source: IBM



Source: Google, Mohseni et al., Nature 543 (2017)

1950s

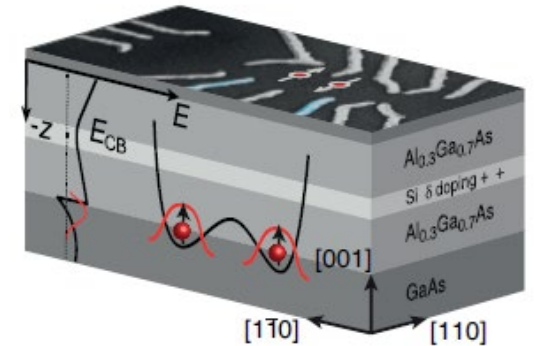


Source: IBM

QUANTUM COMPUTERS

Requirements GaAs Spin Qubits

- Up to 8 uncorrelated bias voltages per qubit, forming potential wells
- 2 pulse electrodes for qubit operation
- Key performance indicator: fidelity of qubit gate



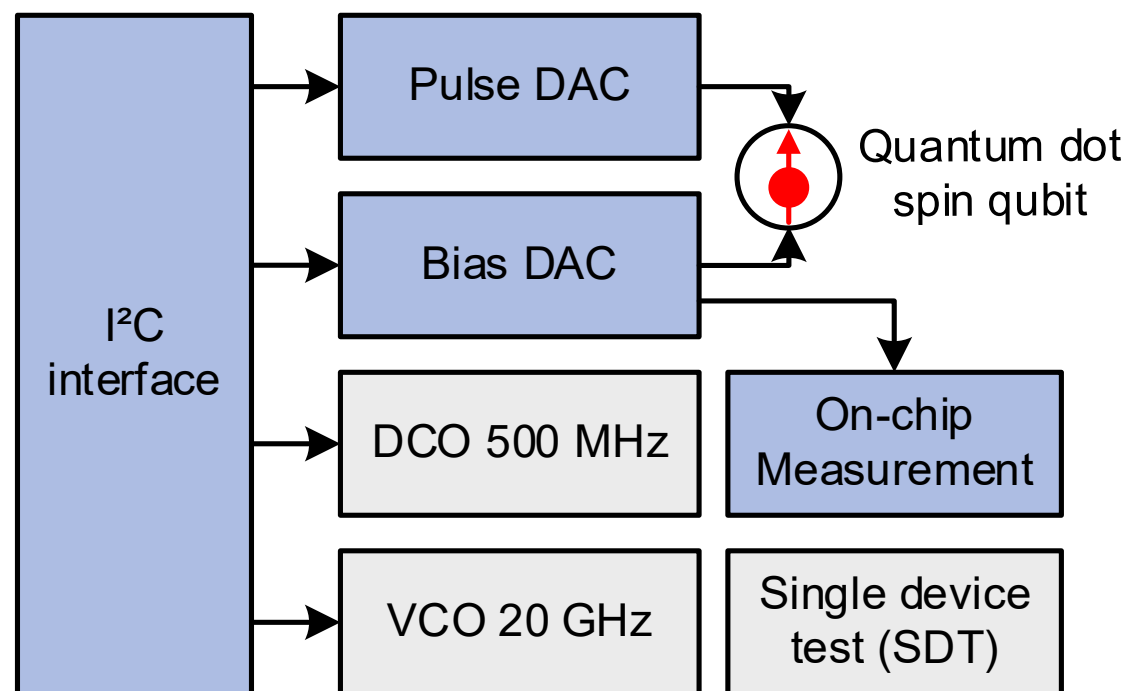
Tim Botzem, "Coherence and high fidelity control of two-electron spin qubits in GaAs quantum dots," PhD Thesis, p. 7, Fig. 2.2.: Device Layout. Online: <http://publications.rwth-aachen.de/record/689507>, 2017, DOI: 10.18154/RWTH-2017-04410

Characteristic	Specification
Bias voltage range	−1 V to 0 V
Bias voltage noise v_{RMS}	$\lesssim 20 \mu\text{V}$
Bias voltage step size	$250 \mu\text{V}$ ($\triangleq 12 \text{ bit}$)
Pulse dynamic range	$\pm 4 \text{ mV}$
Pulse sampling rate	250 MHz
Pulse resolution (8 mV range)	$30 \mu\text{V}$ ($\triangleq 8 \text{ bit}$)
Cooling power budget @ 100 mK	<1 mW

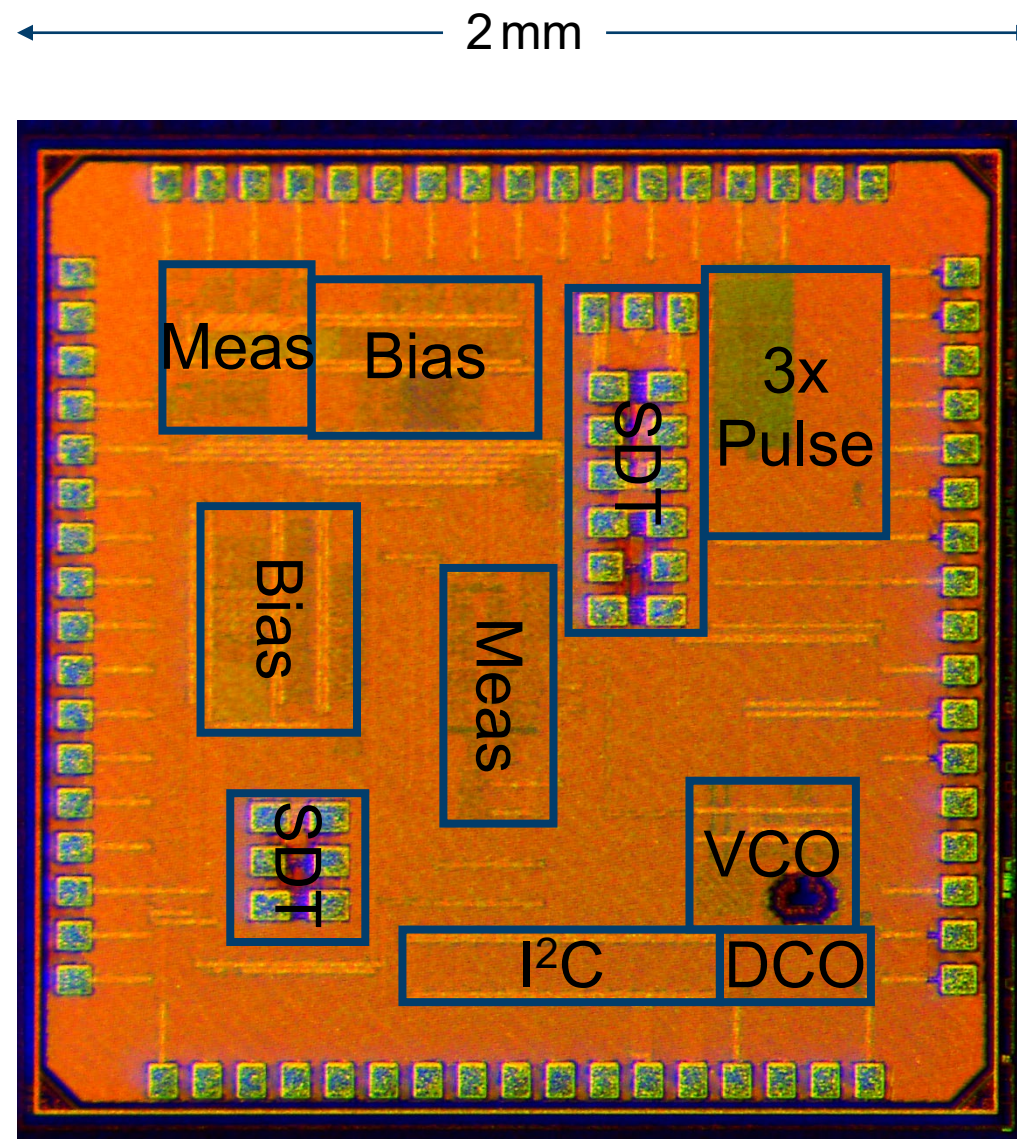
SQUBIC1

Scalable Quantum Bit Control

- TSMC 65nm CMOS technology
- Biasing and pulse control of GaAs qubit



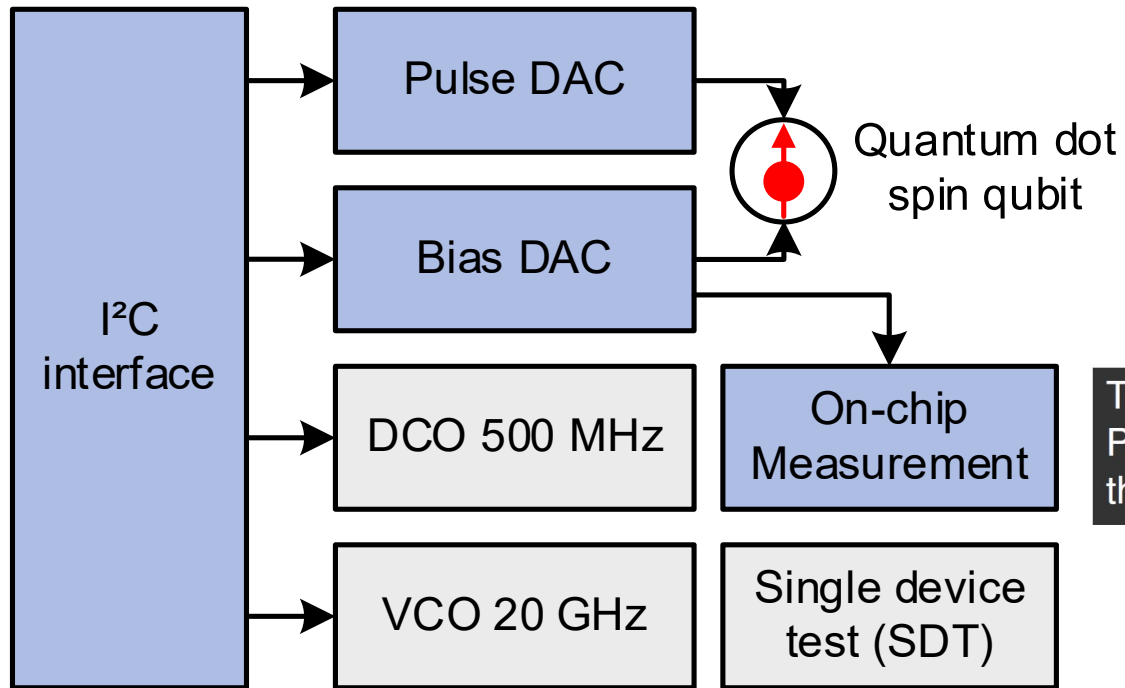
2mm



SQUBIC1

Measurement Setup

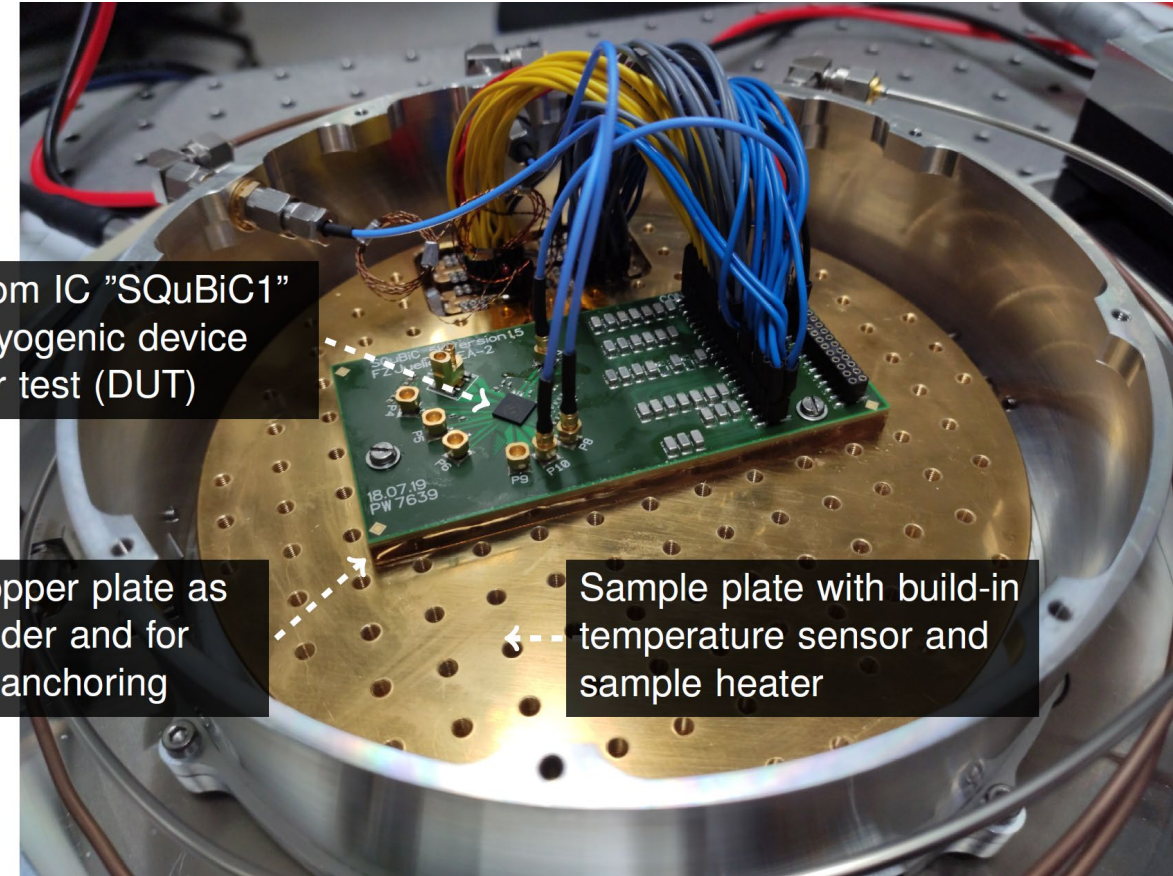
- Packaged sample inside cryostat
- Cryostat base temperature approx. 6 K



Custom IC "SQUBIC1" as cryogenic device under test (DUT)

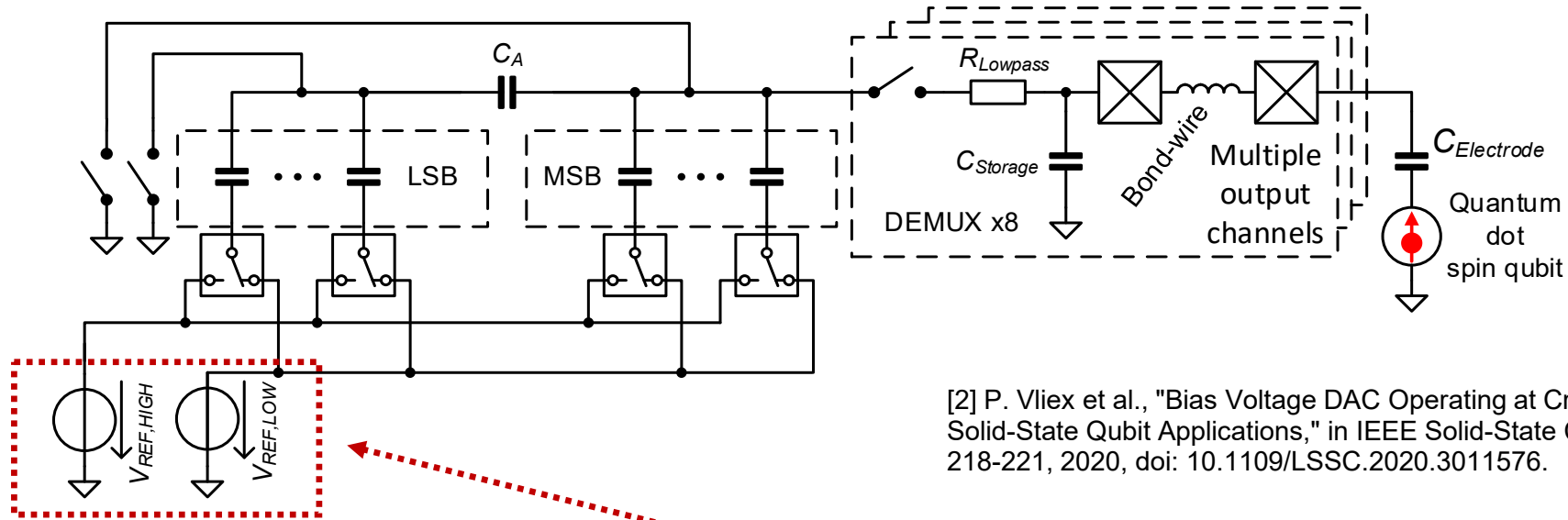
Thick copper plate as PCB holder and for thermal anchoring

Sample plate with build-in temperature sensor and sample heater



BIAS DAC

Charge-Redistribution Topology



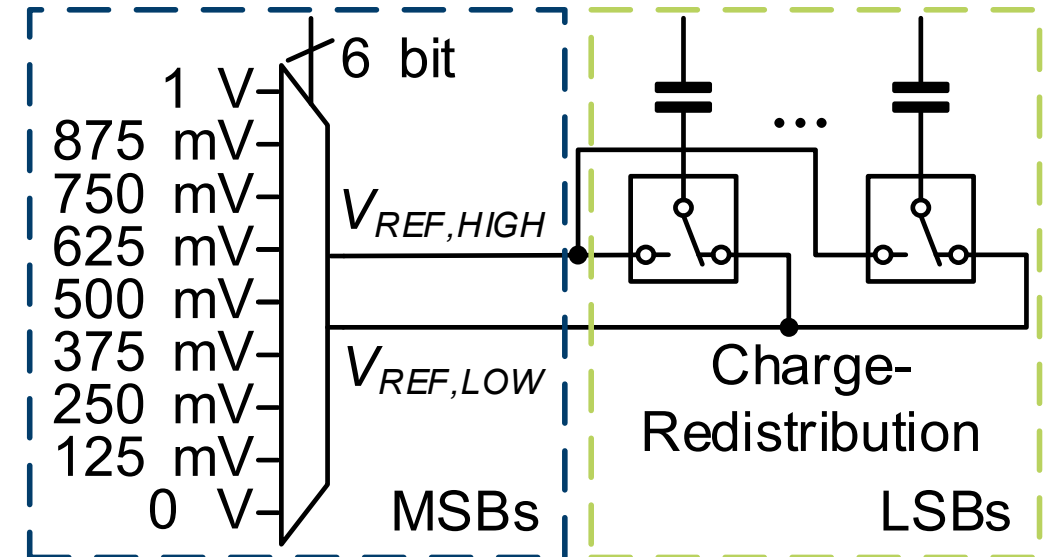
- Negligible static power dissipation
- Low thermal noise at cryo. T : $\bar{v}_N^2 = \frac{k_B \cdot T}{C}$
- No output buffer needed
→ Reduce power and noise
- Coarse tuning by on-chip MUX^[2]
→ Reduce power and increase resolution
→ But: need for calibration
- Multiple output channels per DAC

BIAS DAC

Coarse Tuning Reference Voltages

- Coarse tuning by on-chip MUX^[2]
 - Reduce dynamic analog power P_{AD}
$$\Delta V_{REF} = V_{REF,HIGH} - V_{REF,LOW}$$
$$P_{AD} \propto C_{Total,DAC} \cdot (\Delta V_{REF})^2 \cdot f$$
 - $P_{AD} \downarrow$ by a factor $(125 \text{ mV} / 1 \text{ V})^2 = 1/64$

- Resolution increased
 - 3 bit added for $V_{REF,HIGH}$ and $V_{REF,LOW}$ each
 - DAC resolution \uparrow by 3 bit

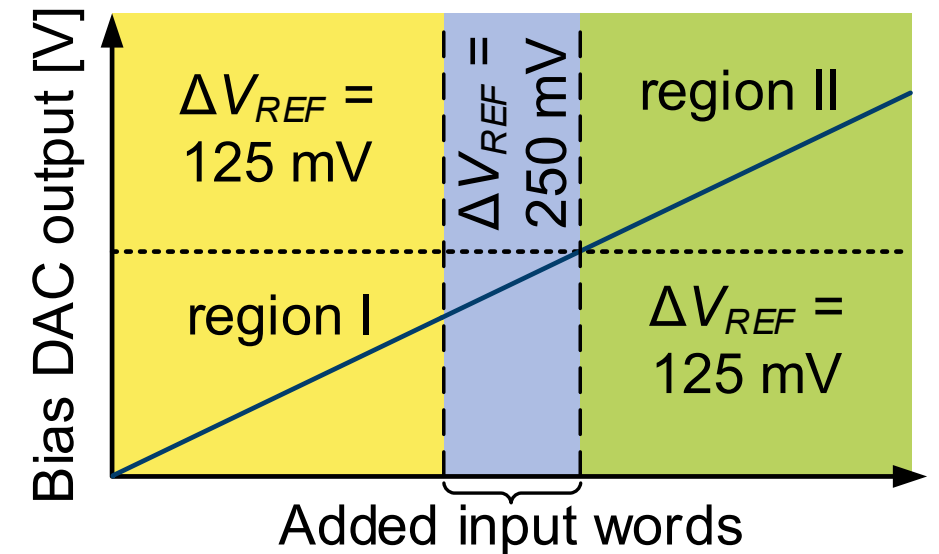
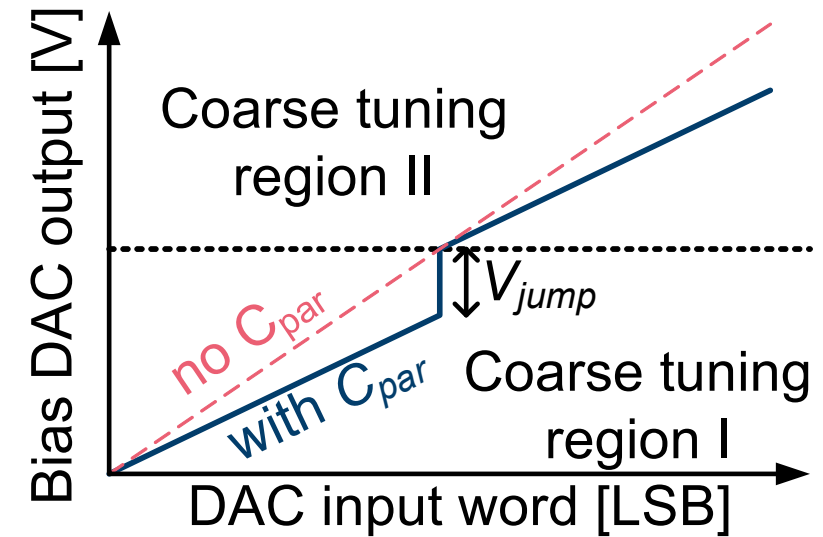


[2] P. Vliex et al., "Bias Voltage DAC Operating at Cryogenic Temperatures for Solid-State Qubit Applications," in IEEE Solid-State Circuits Letters, vol. 3, pp. 218-221, 2020, doi: 10.1109/LSSC.2020.3011576.

BIAS DAC

Coarse Tuning Reference Voltages

- Coarse tuning by on-chip MUX^[2]
- Parasitic C_{par} leads to DAC gain < 1
 - Voltage jump V_{jump} at coarse tuning crossings
- Introduce *intermediate steps*
 - Filling the missing codes range
 - Operated with $\Delta V_{REF} = 250\text{ mV}$
 - Add input words
 - Saved in off-chip memory



[2] P. Vliex et al., "Bias Voltage DAC Operating at Cryogenic Temperatures for Solid-State Qubit Applications," in IEEE Solid-State Circuits Letters, vol. 3, pp. 218-221, 2020, doi: 10.1109/LSSC.2020.3011576.

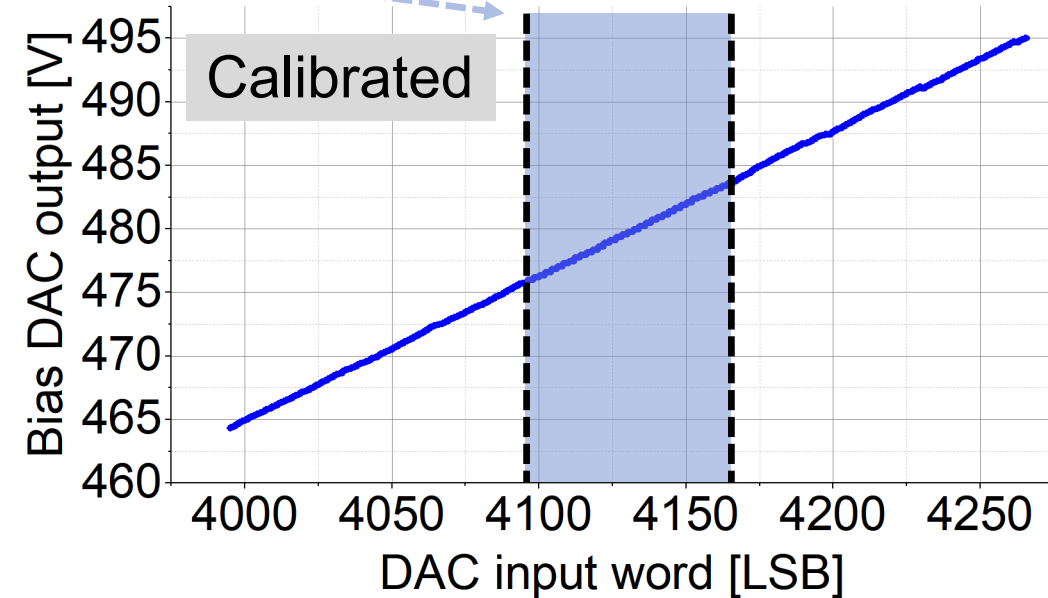
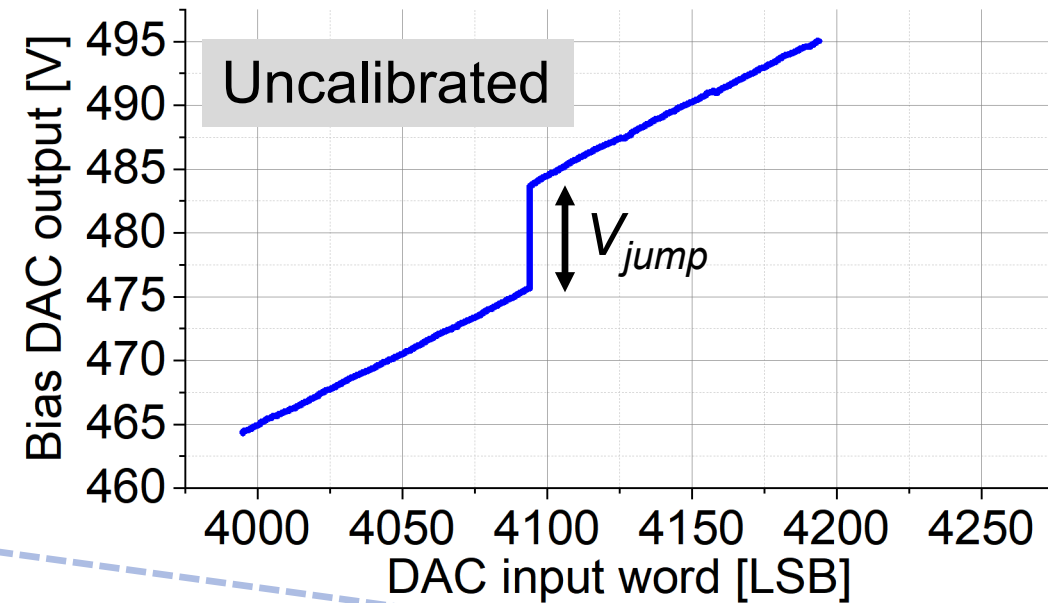
BIAS DAC

Coarse Tuning Reference Voltages

- Calibration verified at 6 K
- *Intermediate steps*
- Steps doubled

→ Correcting Bias DAC gain

	← Intermediate steps range →												
$V_{REF,HIGH}$ 3 bit	3 (500 mV)		4 (625 mV)				...	4 (625 mV)					
$V_{REF,LOW}$ 3 bit			3 (375 mV)				...	3 (375 mV)				4 (500 mV)	
Charge-redistribution 10 bit	1022	1023	502	502	503	503	...	530	530	531	531	0	1
Z_{IN}	4094	4095	4096	4097	4098	4099	...	4152	4153	4154	4155	4156	4157

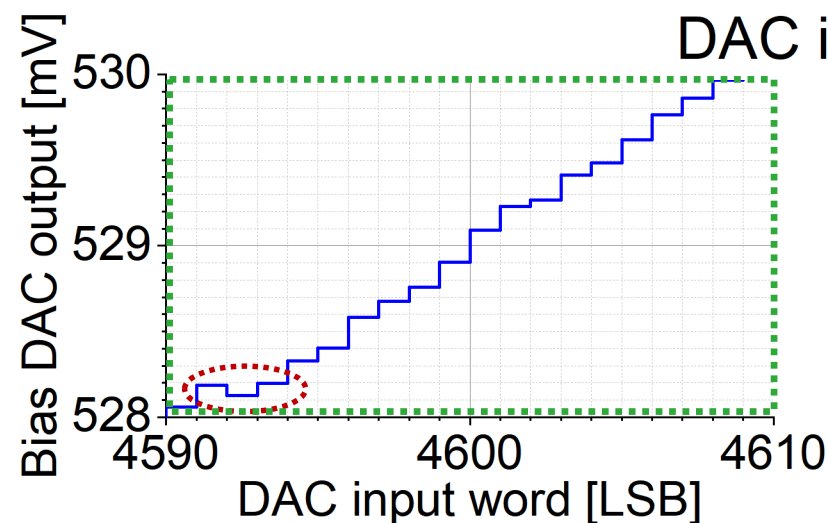
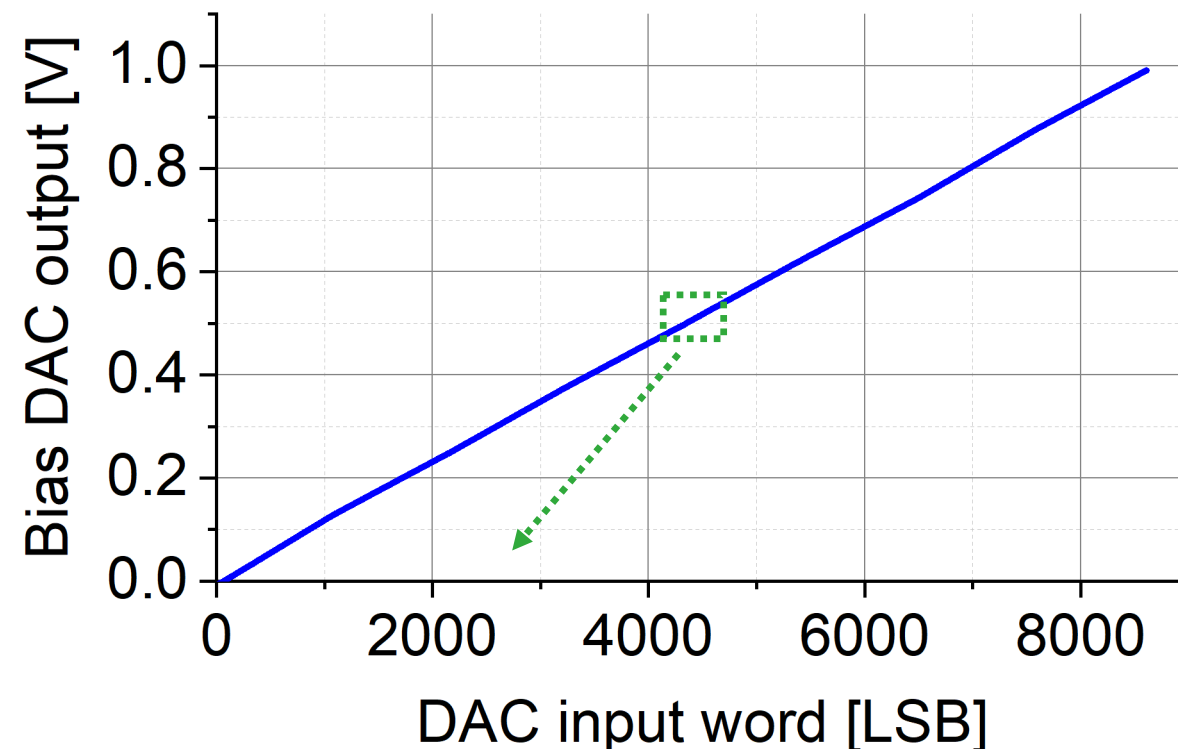


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BIAS DAC

Measurement

- Fully functional at 6 K^[2]
 - 13 bit resolution ($\approx 120 \mu\text{V}$ step size)
 - 1 V output range
 - Channel refresh rate of 3.9 kHz
 - Calibrated reference voltage coarse tuning
- Singular non-monotonic steps
 - No issue for qubit biasing

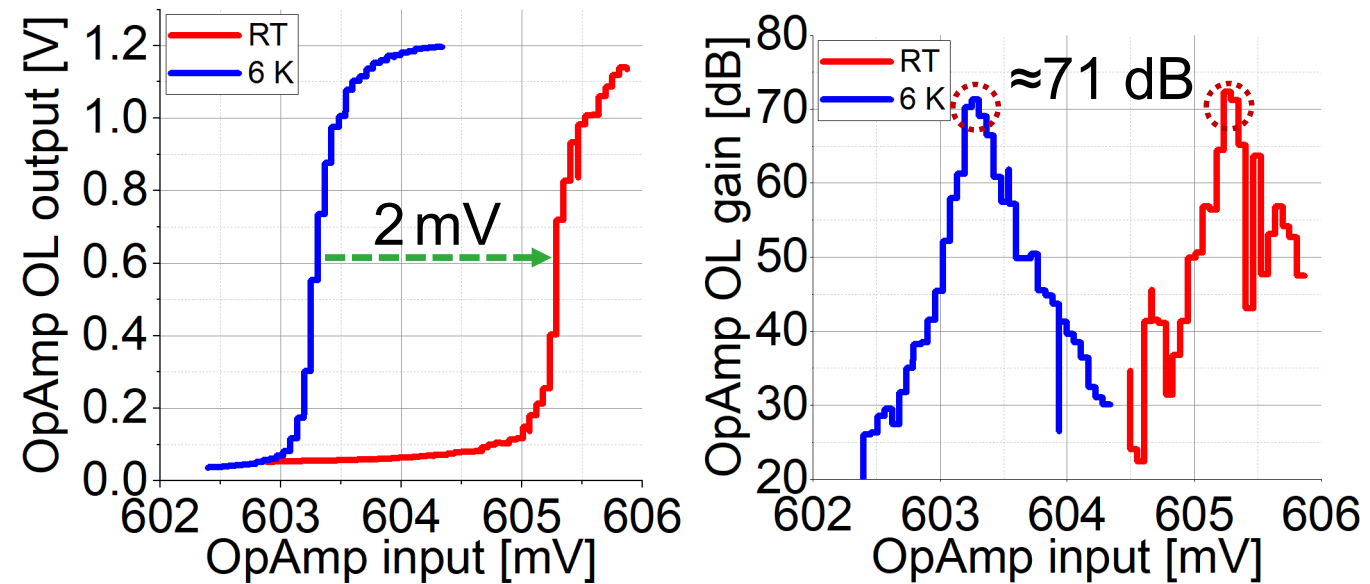
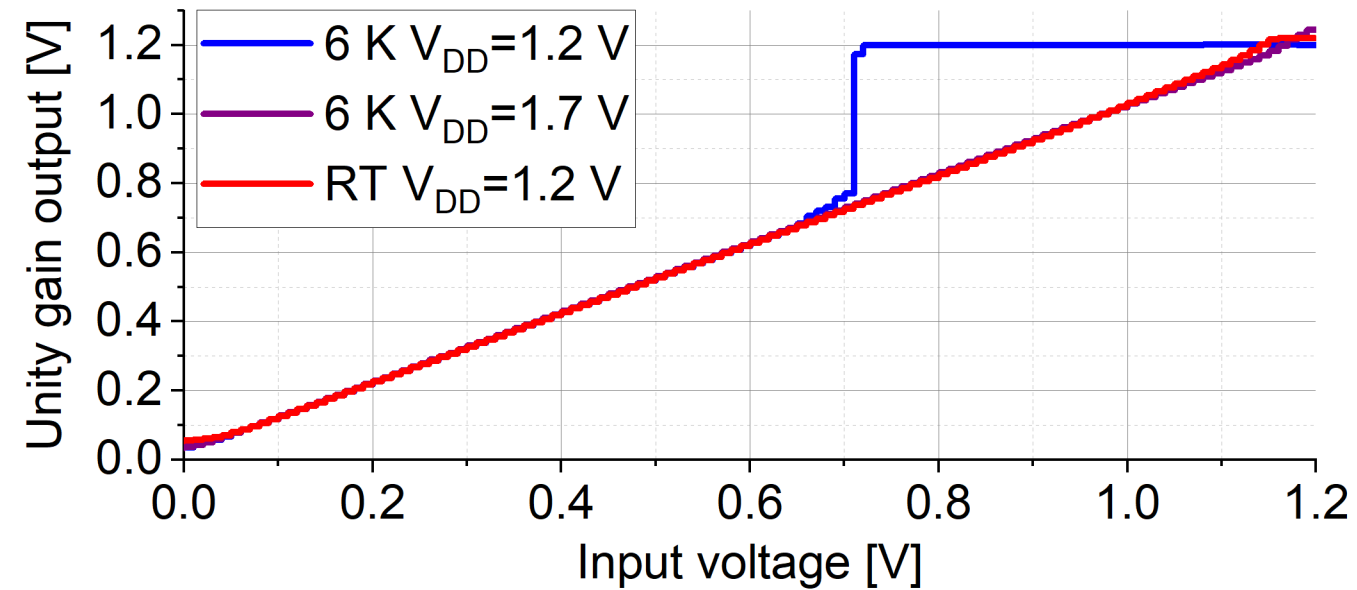


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OPAMP

On-chip Measurement Circuitry

- Unity gain configuration
- Enable Bias DAC noise measurement
- Supply increase: 1.2 V to 1.7 V at 6 K
- Small offset voltage shift of ≈ 2 mV \dashrightarrow
- Comparable open-loop (OL) gain of ≈ 71 dB

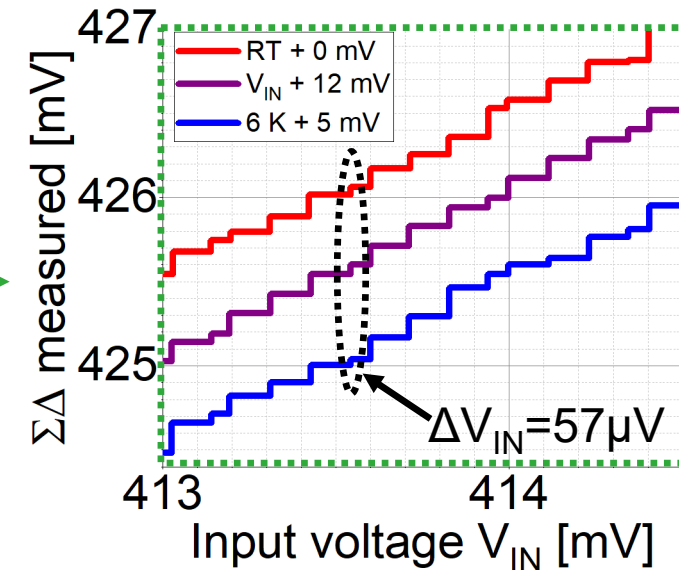
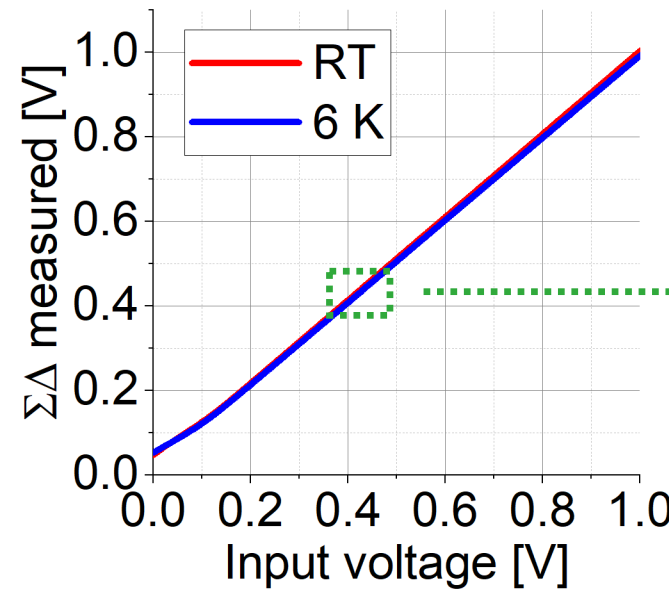
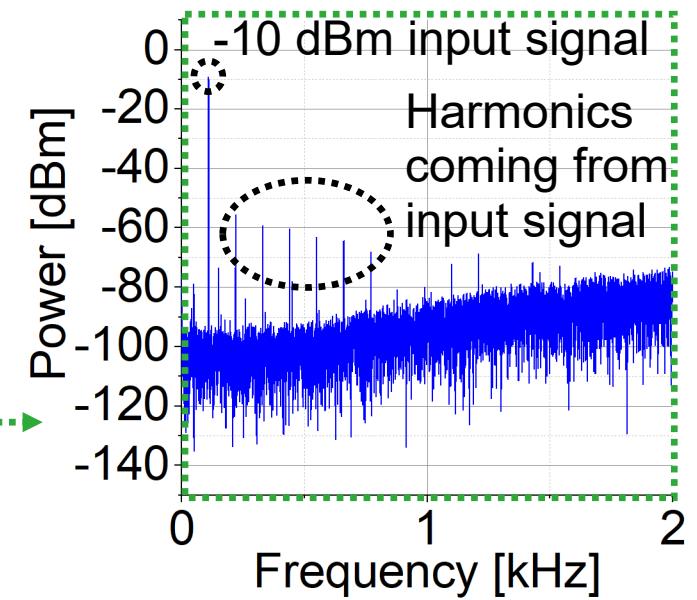
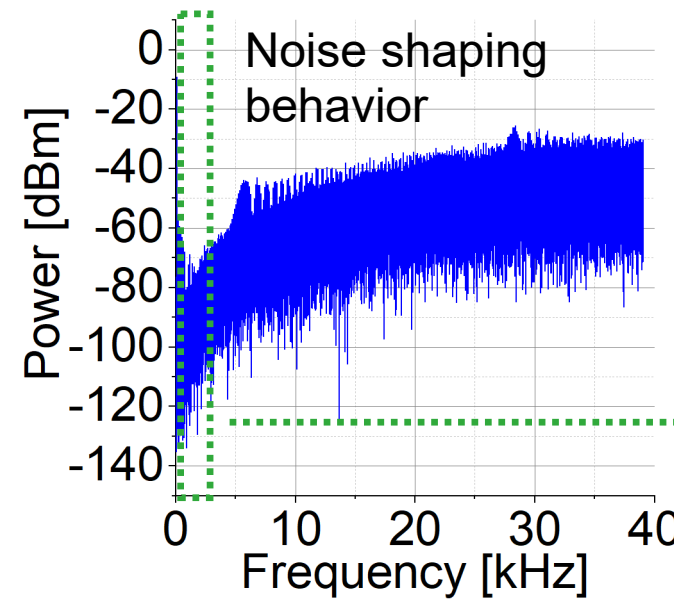


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$\Sigma\Delta$ MODULATOR

On-chip Measurement Circuitry

- Measurement at 6 K
- On-chip analog-to-digital conversion
- 3rd order 2-1 MASH modulator
- Noise floor (≈ -110 dBm) limited by input signal
- Off-chip bit-stream filtering
- Building block for future on-chip Bias DAC calibration



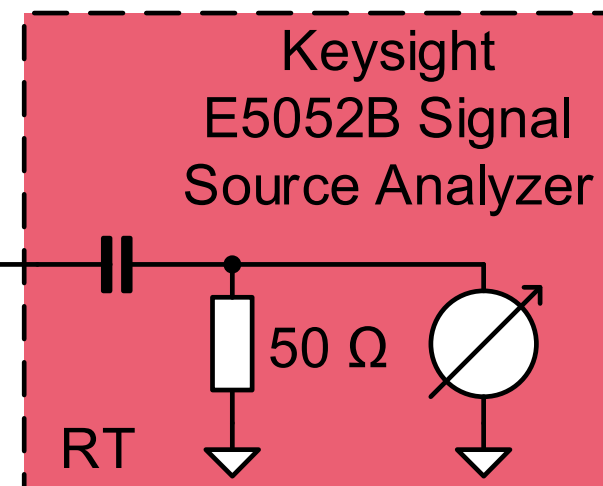
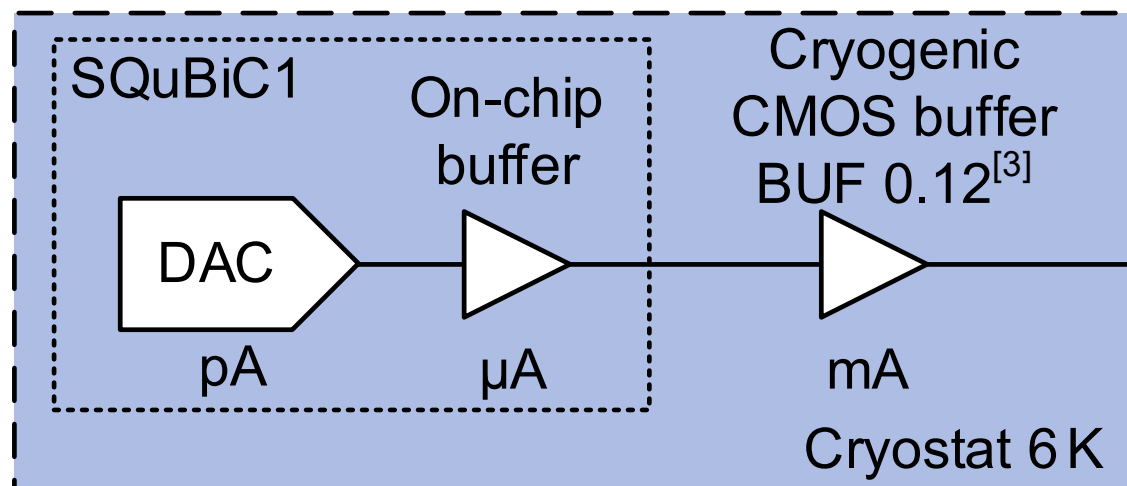
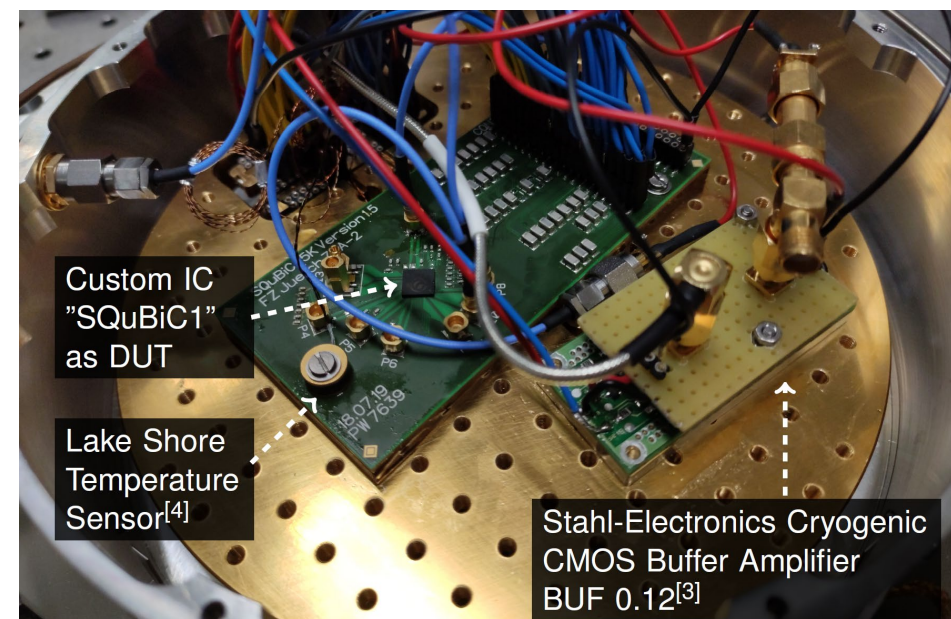
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BIAS DAC

Noise Measurement Setup

- Noise measurement buffer chain (BC)
 - Impedance conversion: high-ohmic $\rightarrow 50 \Omega$
 - Gradually increasing driving capability
 - Commercial cryogenic buffer BUF 0.12^[3]

[4] Lake Shore, DT-670 Silicon Diode, CU package, <https://www.lakeshore.com/products/categories/overview/temperature-products/cryogenic-temperature-sensors/dt-670-silicon-diodes>



[3] Stahl-Electronics, BUF 0.12 Cryogenic CMOS Buffer Amplifier, Datasheet, https://www.stahl-electronics.com/bilder/Datasheet_CryoAmp_BUF_V2-1.pdf

BIAS DAC

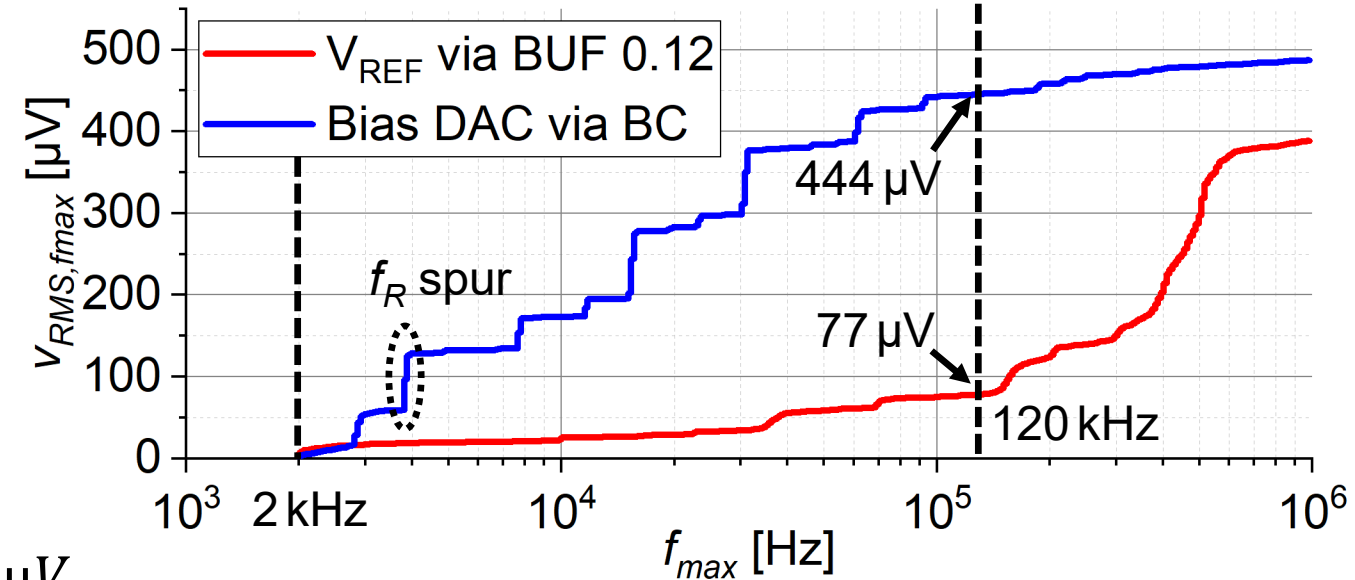
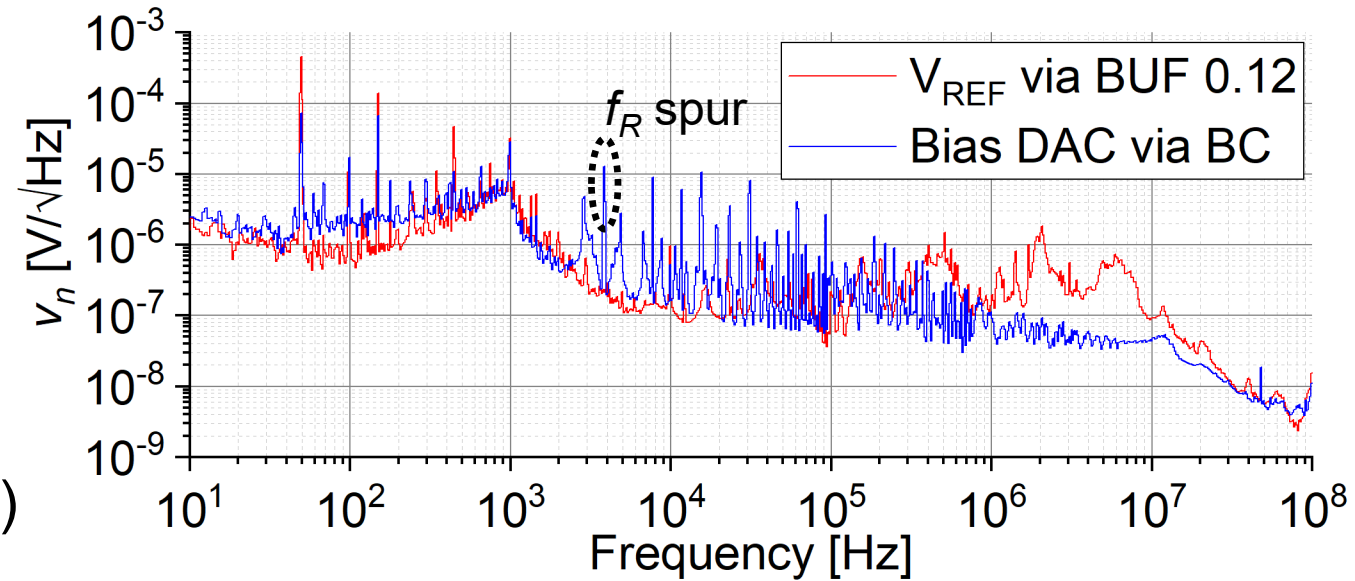
Noise Measurement Results

- Noise integrated from 2 kHz to 120 kHz
 - Exclude 50 Hz (spur from power grid)
 - Exclude 1 kHz (spur from power source)
- BUF 0.12 → DC to 120 kHz
- Bias DAC refresh rate $f_R = 3.9$ kHz

$$v_{RMS,fmax} = \sqrt{\int_{2 \text{ kHz}}^{f_{max}} v_n^2(f) df}$$

- Noise added by Bias DAC

$$v_{RMS,DAC} = \sqrt{(444 \mu V)^2 - (77 \mu V)^2} = 437 \mu V$$





BIAS DAC

Power

[2]

Bias DAC component	Power Consumption
Analog DAC core (slide 7)	77 nW
Analog DAC reference voltages	3 nW
DAC digital (memory & logic)	21 μ W
DAC total	21.1 μ W (2.63 μ W per channel)
Clock buffer	4.3 μ W
Total	25.4 μ W (3.18 μ W per channel)

- 8 Bias DAC channel running and $f_R = 3.9$ kHz
- Ultra-low power consumption ≈ 3 μ W per channel
 - Digital part > 99% \rightarrow Scales well with CMOS technology

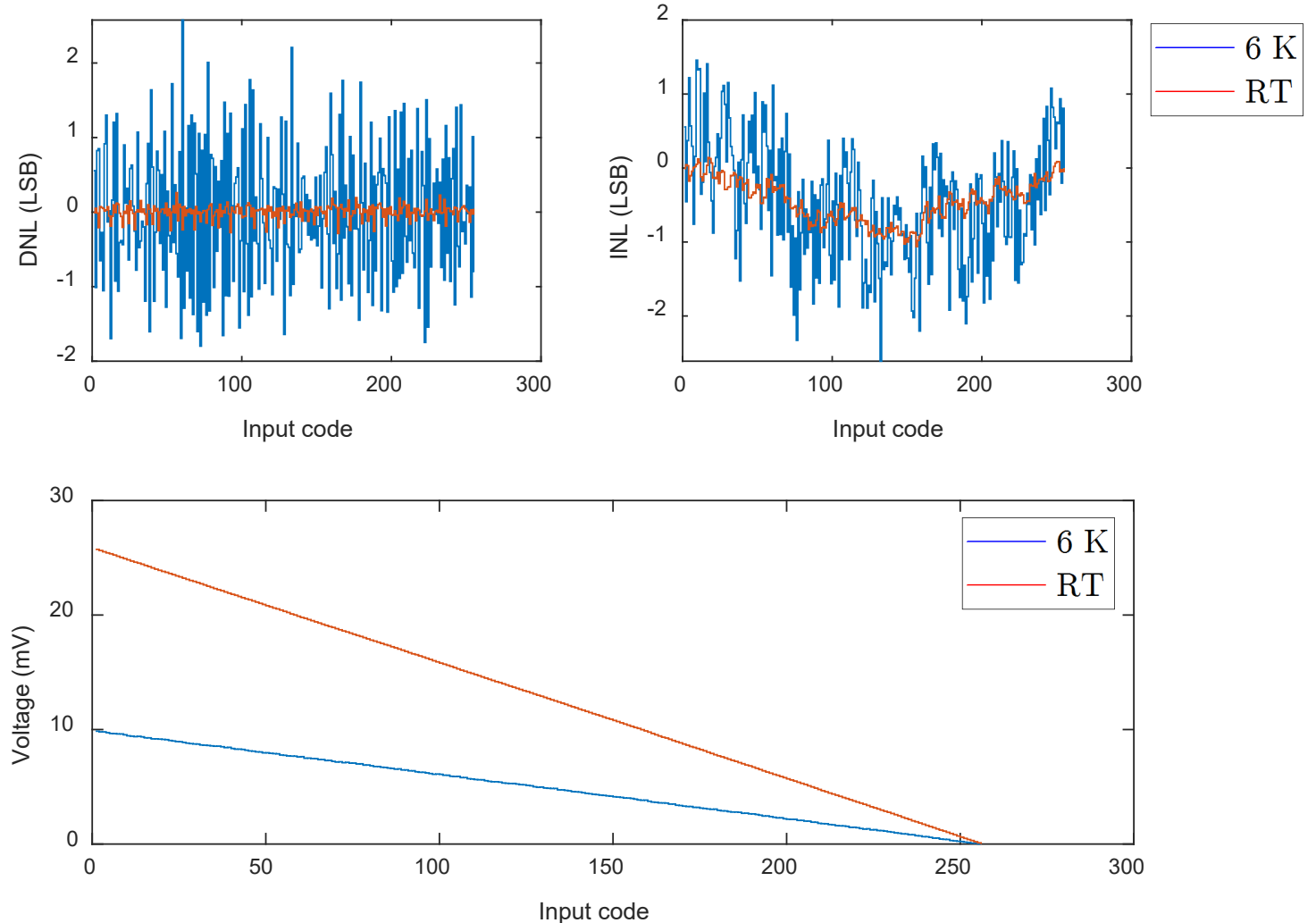
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PULSE DAC

Measurement

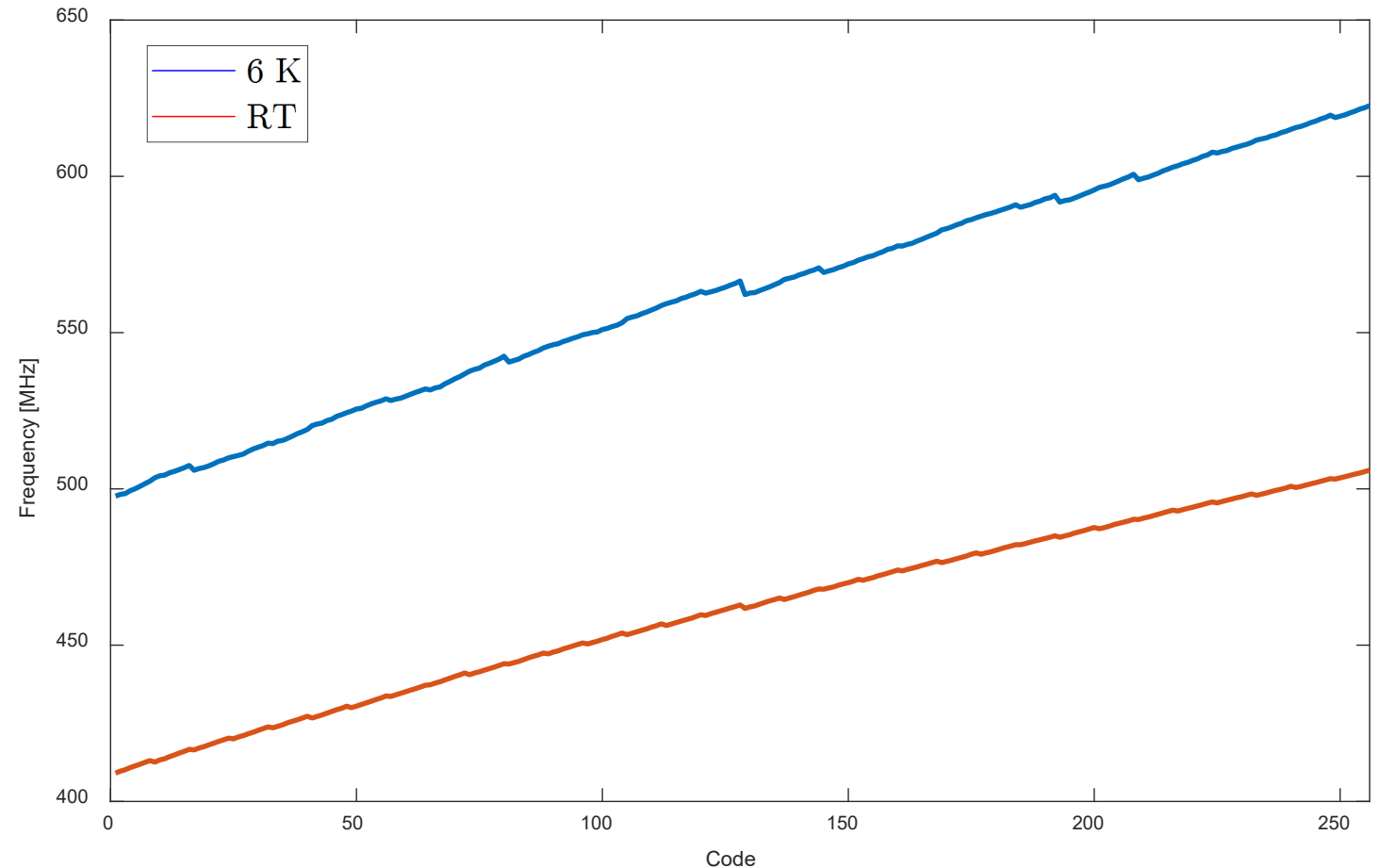
- Current steering DAC
- At cryogenic temperatures INL and DNL worse due to increased mismatch
- Can be improved by calibration



DCO

Digital controlled oscillator

- Current starved ring oscillator
- Frequency shifts to higher frequency at 6 K
- Non monotonic behavior due to mismatch (increased at 6 K)

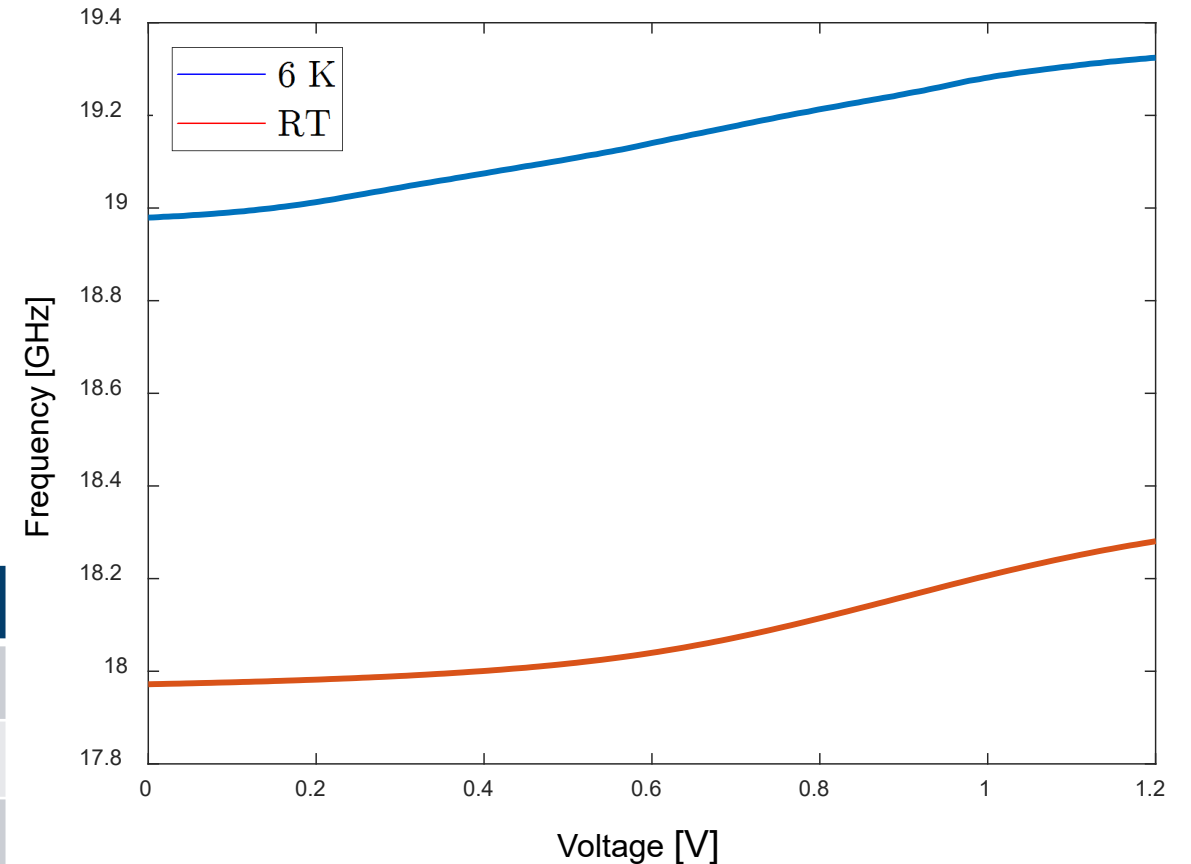


VCO

Voltage controlled oscillator

- LC oscillator
- Center frequency increased by ~5%
- Smaller gain but increased linear region

Temperature	300 K	6 K
KVCO	425 MHz/V	375 MHz/V
Frequency-span	310 MHz	324 MHz
Center-frequency	18.12 GHz	19.15 GHz



SUMMARY

Outlook

- SQuBiC1: IC for local qubit biasing and control
 - Incl. additional measurement and support circuitry
- Promising performance results at 6 K
 - All circuits are tuned operational
- Next steps:
 - Ongoing effort to test with a qubit sample (Prof. Bluhm's group at RWTH Aachen)
 - SQuBiC1 on 100 mK interposer

